

EV850817289

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 10/734,072
 Confirmation No. 8908
 Filing Date December 10, 2003
 Inventor Mark E. Tuttle et al.
 Assignee Micron Technology, Inc.
 Group Art Unit 2825
 Examiner Caridad Everhart
 Customer No. 021567
 Attorney Docket No. MI40-369
 Title: Methods for Forming Integrated Circuits Within Substrates

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT****References -- See Attached Form PTO-1449**

The attached Form PTO-1449 is submitted in compliance with 37 CFR §§ 1.56, 1.97 and 1.98. Pursuant to *FEDERAL REGISTER*, Vol. 69, No. 182, pg. 56542 (September 21, 2004), only copies of the cited foreign references are enclosed herewith. No admission is made regarding whether the listed references are prior art.

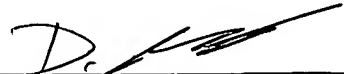
The cited references contained in the Supplemental Information Disclosure Statement were first cited in a communication from the German Patent Office in a counterpart German application not more than three months prior to the filing of this statement. See 37 C.F.R. § 1.97(e). Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. § 1.17(p) to Deposit Account No. 23-0925.

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Respectfully submitted,

Dated: June 16, 2006
 By: 
 Deepak Malhotra
 Reg. No. 33,560

Form PTO-1449

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PATENT DOCKET NO.
MI40-369SERIAL NO.
10/734,072U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEAPPLICANT
MARK E. TUTTLE ET AL.FILING DATE
DEC. 10, 2003GROUP
2891

LIST OF ART CITED BY APPLICANT

(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AA	3,706,094	12/1972	COLE ET AL	342	44	
AB	3,750,167	07/1973	GEHMAN ET AL.	342	44	
AC	3,780,368	12/1973	NORTHEVED ET AL.	342	44	
AD	3,832,530	08/1974	REITBOCK ET AL.	342	44	
AE	3,849,633	11/1974	REITBOCK ET AL.	235	487	
AF	4,049,969	09/1977	SALONIMER ET AL.	356	5	
AG	4,331,957	05/1982	ENANDER ET AL.	342	22	
AH	4,399,441	11/1983	VAUGHAN ET AL.	342	50	
AI	4,412,356	10/1983	KLAUS ET AL.	455	603	
AJ	4,418,411	11/1983	STREITZEL	340	870.16	

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						Yes	No
AK	DE 41 20 265 A1	6/1991	Germany (Mitsubishi) See US 5,274,221 (prev. cited)	G06K	7/01	Abs	
AL	GB 1 567 784	5/1980	United Kingdom	G06K	19/00		
AM	JP 1-191082	8/1989	Japan (Sony Corp.)	G01S	013/74	Abs	

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AN	CASSON, K., et al., "High Temperature Packaging: Flip Chip on Flexible Laminate", <u>Surface Mount Technology</u> , pp. 19-20 (1/1992)
AO	JOHNSON, R.W., "Polymer Thick Films: Technology and Materials", <u>Circuits Manufacturing</u> (reprint), 4 pages (7/1982)
AP	GILLES, K., "Using SM Devices on Flexible Circuitry", <u>ELECTRI-ONICS</u> , pp. 20-23 (3/1986)

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449		EV850817285			DOCKET NO. MI40/369		SERIAL NO. 10/734,072	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT MARK E. TUTTLE ET AL.			
					FILING DATE DEC. 10, 2003		GROUP 2891	
U.S. PATENT DOCUMENTS								
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	AA	4,484,355	11/1984	HENKE ET AL.	455	76		
	AB	4,539,472	09/1985	POETKER ET AL.	235	488		
	AC	4,724,340	05/1988	NOWIK ET AL.	340	572		
	AD	4,724,427	02/1988	CARROLL	340	572		
	AE	4,727,560	02/1988	VAN ZANTEN ET AL.	377	60		
	AF	4,746,618	05/1988	NATH ET AL.	437	2		
	AG	4,746,830	05/1988	HOLLAND	310	313		
	AH	4,756,717	07/1988	STURGIS ET AL.	427	290		
	AI	4,777,563	10/1988	TERAOKA ET AL.	361	395		
	AJ	4,783,646	11/1988	MATSUZAKI	340	572		
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							Yes	No
	AK	JP 2-179794	7/1990	Japan (Sony Corp.)	B42D	015/10	Abs	
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	AN	KANATZIBIS, Mercuri G. "Conductive Polymers", <u>Chemical and Engineering News--American Chemical Society</u> , pp. 36-54 (12/1990)						
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	AB	4,827,395	05/1989	ANDERS ET AL.	364	138		
	AC	4,854,328	08/1989	POLLACK	128	736		
	AD	4,911,217	03/1990	DUNN ET AL.	152	152.1		
	AE	4,918,631	04/1990	HARA ET AL.	364	708		
	AF	4,942,327	07/1990	WATANABE ET AL.	310	313 R		
	AG	4,962,415	10/1990	YAMAMOTO ET AL.	357	74		
	AH	5,008,776	04/1991	QUEYSSAC	361	392		
	AI	5,023,573	06/1991	ADAM	333	17.2		
	AJ	5,095,240	03/1992	NYSEN ET AL.	310	313		
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	AK	JP 2-36476	3/1990	Japan (Fijitsu Ltd)	G06F	015/40	Abs	
	AL	0 595 549 A2	10/1993	EPO (Hughes-Microelectronics)	H04Q	9/00	X	
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	AA	5,124,782	06/1992	HUNDT ET AL.	257	724		
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	AC	5,144,314	09/1992	MALMBERG ET AL.	342	44		
	AD	5,148,504	09/1992	LEVI ET AL.	385	14		
	AE	5,153,710	10/1992	McCAIN	357	75		
	AF	5,164,732	11/1992	BRACKELSBY ET AL.	342	44		
	AG	5,175,418	12/1992	TANAKA	235	439		
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	AJ	5,302,954	04/1994	BROOKS ET AL.	342	44		
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	AA	5,313,211	05/1994	TOKUDA ET AL.	340	50		
	AB	5,317,309	05/1994	VERCELLOTTI ET AL.	340	825		
	AC	5,337,063	05/1994	TAKAHIRA	343	741		
	AD	5,340,968	09/1994	WATANABE ET AL.	235	380		
	AE	5,347,263	09/1994	CARROLL ET AL.	340	825		
	AF	5,414,427	05/1995	GUNNARSON	342	825		
	AG	5,448,110	09/1995	TUTTLE ET AL.	257	723		
	AH	5,497,140	03/1996	TUTTLE	342	51		
	AI	5,541,399	07/30/96	DE VALL	235	491		
	AJ	5,572,226	11/1996	TUTTLE	343	726		
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	AA	5,719,586	02/19981	TUTTLE ET AL.	343	726		
	AB	5,776,278	07/1998	TUTTLE ET AL.	156	213		
	AC	5,779,839	07/1998	TUTTLE ET AL.	156	213		
	AD	5,955,949	09/1999	COCITA	340	572		
	AE	5,982,284	11/1999	BALDWIN ET AL.	340	572		
	AF	6,265,977	07/2001	VEGA ET AL.	340	572		
	AG	6,294,998	09/2001	ADAMS ET AL.	340	572		
	AH	5,055,968	10/08/91	NISHI ET AL.	361	395		
	AI	5,166,502	11/24/92	RENDLEMAN ET AL.	235	492		
	AJ	4,857,893	08/15/89	CARROLL	340	572		
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